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NOTICE OF ALLOWANCE AND FEE(S) DUE

7590

09/26/2008

Wells St. John P.S. 601 W. First Ave., Suite 1300 Spokane, WA 99201

EXAMINER				
SMYTH, ANDREW P				
ART UNIT	PAPER NUMBER			
2881				

DATE MAILED: 09/26/2008

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/554,039	10/20/2005	Dennis Barket JR.	GR61-043	1055

TITLE OF INVENTION: INSTRUMENTATION, ARTICLES OF MANUFACTURE, AND ANALYSIS METHODS

APPLN. TYPE	SMALL ENTITY	ISSUE FEE DUE	PUBLICATION FEE DUE	PREV. PAID ISSUE FEE	TOTAL FEE(S) DUE	DATE DUE
nonprovisional	YES	\$720	\$300	\$0	\$1020	12/26/2008

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THE ISSUE FEE AND PUBLICATION FEE (IF REQUIRED) MUST BE PAID WITHIN THREE MONTHS FROM THE MAILING DATE OF THIS NOTICE OR THIS APPLICATION SHALL BE REGARDED AS ABANDONED. THIS STATUTORY PERIOD CANNOT BE EXTENDED. SEE 35 U.S.C. 151. THE ISSUE FEE DUE INDICATED ABOVE DOES NOT REFLECT A CREDIT FOR ANY PREVIOUSLY PAID ISSUE FEE IN THIS APPLICATION. IF AN ISSUE FEE HAS PREVIOUSLY BEEN PAID IN THIS APPLICATION (AS SHOWN ABOVE), THE RETURN OF PART B OF THIS FORM WILL BE CONSIDERED A REQUEST TO REAPPLY THE PREVIOUSLY PAID ISSUE FEE TOWARD THE ISSUE FEE NOW DUE.

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10/554,039 TITLE OF INVENTION	10/20/2005 i: INSTRUMENTATION	N, ARTICLES OF MANU	Dennis Barket JR UFACTURE, AND AN		YSIS METHODS		GR61-043		1055
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nonprovisional	YES	\$720	\$300		\$0		\$1020		12/26/2008
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SMYTH, A	ANDREW P	2881	250-288000	_					
CFR 1.363). Change of corresp Address form PTO/SI "Fee Address" ind PTO/SB/47; Rev 03-(Number is required. ASSIGNEE NAME A PLEASE NOTE: Un	ND RESIDENCE DATA	inge of Correspondence	data will appear on the	ip to rnative single or a attor il be por typ	3 registered patentely, e firm (having as a gent) and the namneys or agents. If printed. e) tent. If an assign	t attorn membes of uno nam	er a 2 p to le is 3	locum	ent has been filed for
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Spokane, WA 9920)1		2881		
			DATE MAILED: 09/26/2008		

Determination of Patent Term Adjustment under 35 U.S.C. 154 (b)

(application filed on or after May 29, 2000)

The Patent Term Adjustment to date is 446 day(s). If the issue fee is paid on the date that is three months after the mailing date of this notice and the patent issues on the Tuesday before the date that is 28 weeks (six and a half months) after the mailing date of this notice, the Patent Term Adjustment will be 446 day(s).

If a Continued Prosecution Application (CPA) was filed in the above-identified application, the filing date that determines Patent Term Adjustment is the filing date of the most recent CPA.

Applicant will be able to obtain more detailed information by accessing the Patent Application Information Retrieval (PAIR) WEB site (http://pair.uspto.gov).

Any questions regarding the Patent Term Extension or Adjustment determination should be directed to the Office of Patent Legal Administration at (571)-272-7702. Questions relating to issue and publication fee payments should be directed to the Customer Service Center of the Office of Patent Publication at 1-(888)-786-0101 or (571)-272-4200.

	Application No.	Applicant(s)			
	10/554,039	BARKET ET AL.			
Notice of Allowability	Examiner	Art Unit			
	AND DEM ON THE	0004			
	ANDREW SMYTH	2881			
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED i or other appropriate comm GHTS. This application is	n this application. If not included unication will be mailed in due cou	rse. THIS		
1. This communication is responsive to <u>06/24/2008</u> .					
2. \boxtimes The allowed claim(s) is/are $\underline{13,6,7,1015,1726}$ and $\underline{3650}$					
 3. ☐ Acknowledgment is made of a claim for foreign priority ur a) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority do 	been received. been received in Application	on No	from the		
International Bureau (PCT Rule 17.2(a)).	difficilità fiave been receive	a in this hational stage application	nom the		
* Certified copies not received:					
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	IENT of this application.				
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give			ICE OF		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	et be submitted.				
(a) \square including changes required by the Notice of Draftspers	on's Patent Drawing Revie	w (PTO-948) attached			
1) 🔲 hereto or 2) 🔲 to Paper No./Mail Date					
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment o	r in the Office action of			
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t			ck) of		
6. DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT			e the		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. ☐ Notice of Ir	nformal Patent Application			
2. \square Notice of Draftperson's Patent Drawing Review (PTO-948)		ummary (PTO-413),			
Paper No./Mail Date 3. ☑ Information Disclosure Statements (PTO/SB/08), 7. ☐ Examiner's Amendment/Comment					
Paper No./Mail Date See Continuation Sheet					
4. Examiner's Comment Regarding Requirement for Deposit of Biological Material		Statement of Reasons for Allowar	nce		
(India I Boundary)	9.	<u>-</u> .			
/Jack I. Berman/ Primary Examiner, Art Unit 2881					
. Timely Examinor, the one 2001					

Continuation of Attachment(s) 3. Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date: 01/20/2006; 10/10/2006; 10/03/2007.

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DETAILED ACTION

Response to Amendment

- 1. Claims 1, 6, 7, 10, 17-20, 22, 36, and 44 amended.
- 2. Claims 4-5, 8-9, 16, 27-35, and 51 canceled.

Allowable Subject Matter

- 1. Claims 1-3, 6-7, 10-15, 17-26, and 36-50 are allowed.
- 2. The configuration was not found in a prior art search. The following is a listing/statement of reasons for the indication of allowable subject matter.

The search failed to show or suggest the prior use of:

The configuration/ combination of elements of independent claim 1 An instrument comprising:

an ionization source configured to apply different ionization energies to a sample to provide different sample characteristics; and

processing circuitry configured to process the different sample characteristics to identify the sample;

wherein the processing circuitry is configured to acquire at least two data sets of the different sample characteristics, one of the two data sets of the different sample characteristics comprising a first sample characteristic associated with a first ionization energy and another of the two data sets of the different sample characteristics comprising a second sample characteristic associated with a second ionization energy; and

wherein the processing circuitry is further configured to access at least two data sets of reference sample characteristics, one of the data sets of the reference sample characteristics comprising a third reference sample characteristic associated with the first ionization energy and another of the two data sets of the reference sample characteristics comprising a fourth reference sample characteristic associated with the second ionization energy.

The configuration/ combination of elements of independent claim 7 Amass spectrometer comprising:

an ionization component configured to receive a sample and provide a first ionization energy to the sample to form a first ionized analyte and provide a second ionization energy to the sample to form a second ionized analyte, wherein the first and second energies are not equal;

a detection component configured to detect the first and second ionized analytes formed by the ionization component; a4q-el-

processing circuitry configured to monitor the detection component and associate detection of the first ionized analytes with a first sample characteristic and associate detection of the second ionized analytes with a second sample characteristic, wherein the processing circuitry is further configured to associate both the first sample characteristic with the first ionization energy, and the second sample characteristic with the second ionization energy to identify a sample;

wherein the sample characteristics comprise mass spectra and the processing circuitry is further configured to prepare a sample data set comprising first and

second data sets, the first data set comprising the first mass spectra associated with the first ionization energy and the second data set comprising second mass spectra associated with the second ionization energy; and further comprising storage circuitry comprising media configured to store digital data, wherein the media comprises reference data comprising third and fourth data sets, the third data set comprising a third mass spectra and the first ionization energy and the fourth data set comprising a fourth mass spectra and the second ionization energy, wherein the third mass spectra was acquired at the first ionization energy and the fourth mass spectra was acquired at the second ionization energy.

The configuration/ combination of elements of independent claim 20 Amass spectrometer comprising:

an ionization component configured to receive a sample and provide a first ionization energy to the sample to form a first ionized analyte and provide a second ionization energy to the sample to form a second ionized analyte, wherein the first and second energies are not equal;

a detection component configured to detect the first and second ionized analytes formed by the ionization component;

processing circuitry configured to monitor the detection component and associate detection of the first ionized analytes with a first sample characteristic and associate detection of the second ionized analytes with a second sample characteristic, wherein the processing circuitry is further configured to associate

both the first sample characteristic with the first ionization energy, and the second sample characteristic with the second ionization energy to identify a sample;

a mass separation component configured to receive the first and second ionized analytes from the ionization component and provide a first separation waveform to separate a first mass-to-charge ratio range of ionized analytes and provide a second separation waveform to separate a second mass-to-charge ratio range of ionized analytes; and

wherein the processing circuitry is further configured to associate both the first sample characteristic with the first mass separation waveform, and the second sample characteristic with the second mass separation waveform; and, storage circuitry comprising media configured to store the sample data set and a reference data set, the reference data set comprising third and fourth data sets, the third data set comprising a third sample characteristic of a reference sample associated with the first ionization energy and mass separation waveforms and the fourth data set comprising a fourth sample characteristic of the reference sample associated with the second ionization energy and mass separation waveforms, wherein the third sample characteristic was acquired utilizing the first ionization energy and mass separation waveforms and the fourth sample characteristic was acquired utilizing the second ionization energy and mass separation waveforms.

The configuration/ combination of elements of independent claim 22 Amass spectrometer comprising:

a first analyte modification component configured to receive a sample and provide both a first ionization energy to the sample to form a first group of ionized analytes, and provide a second ionization energy to the sample to form a second group of ionized analytes;

a first mass separation component configured to receive the first and second groups of ionized analytes and provide both a first separation waveform to separate a first mass-to-charge ratio range of the first group of ionized analytes, and provide a second separation waveform to separate a second mass-to-charge ratio range of the second group of ionized analytes;

a second analyte modification component configured to receive the first and second mass-to-charge ratio ranges of ionized analytes and provide both a third energy to the first and second ranges of ionized analytes to form a third group of ionized analytes, and provide a fourth energy to the ranges to form a fourth group of ionized analytes;

a second mass separation component configured to receive the third and fourth groups of ionized analytes and provide both a third separation waveform to separate a third mass-to-charge ratio range of the third group of ionized analytes and provide a fourth separation waveform to separate a fourth mass-to-charge ratio range of the fourth group of ionized analytes, wherein at least one of the first and second or third and fourth ionization energies, or the first and second or

third and fourth separation waveforms are not equal;

a detection component configured to detect the ionized analytes of the third and fourth ranges of ionized analytes received from the second mass separation component; and

processing circuitry configured to monitor the detection component and associate detection of ionized analytes of the third range with a first sample characteristic and associate detection of ionized analytes of the fourth range with a second sample characteristic, wherein the processing circuitry is further configured to correlate both the first sample characteristic with one or more of the first ionization energy, the first mass separation waveform, the third energy and the third mass separation waveform, and the second sample characteristic with one or more of the second ionization energy, the second mass separation waveform, fourth ionization energy, and the fourth separation waveform.

The configuration/ combination of elements of independent claim 36 A sample analysis method comprising: providing a sample; generating a sample data set using the sample, the sample data set comprising first and second data sets, wherein each of the first and second data sets comprises at least one of an analytical parameter value and a sample characteristic acquired using the analytical parameter value, wherein the analytical parameter value of the first set is different than the analytical parameter value of the second se

using the first and the second data sets, identifying the sample. sample;

wherein the sample characteristic comprises at least mass spectra and the

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identifying the sample further comprises:

providing a reference data set comprising third and fourth data sets, the third data set comprising the analytical parameter value of the first set and mass spectra of a reference sample ,generated using the analytical parameter value of the first set, and the fourth data set comprising the analytical parameter value of the second set and mass spectra of the reference sample ,generated using the analytical parameter value of the second set; and comparing the sample and reference data sets, the comparing comprising applying an algorithm to both the mass spectra of the first data set and the third data set, and the mass spectra of the second data set and the fourth data set, wherein the algorithm is configured to compare mass spectra and provide a first match value of the mass spectra of the first data set and the mass spectra of the third data set and a second match value of the mass spectra of the second data set and the mass spectra of the fourth data set.

- 3. Dependent claims 2-3 and 6 are allowable due to dependency upon allowable independent claim 1.
- 4. Dependent claims 10-15 are allowable due to dependency upon allowable independent claim 7.
- 5. Dependent claims 17-19 and 21 are allowable due to dependency upon allowable independent claim 20.

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6. Dependent claims 23-26 are allowable due to dependency upon allowable independent claim 22.

7. Dependent claims 37-50 are allowable due to dependency upon allowable independent claim 36.

Conclusion

1. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Pertinent prior art is closely related art that individually or in combination could be considered grounds for rejection. See references cited for a listing of the pertinent prior art found and the prior art found.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Andrew Smyth whose telephone number is 571-270-1746. The examiner can normally be reached on 7:30AM - 5:00PM; Monday thru Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert Kim can be reached on 571-272-2293. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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/Jack I. Berman/

Primary Examiner, Art Unit 2881

/A. S./ Examiner, Art Unit 2881